

## WEST Search History





DATE: Thursday, February 24, 2005

Hide?	<u>Set</u> <u>Name</u>	<u>Query</u>	<u>Hit</u> <u>Count</u>
	<i>DB=JPAB; PLUR=YES; OP=ADJ</i>		
<input type="checkbox"/>	L14	L13 and overlap\$	3
<input type="checkbox"/>	L13	L12 and gate	90
<input type="checkbox"/>	L12	substrate and cell plate	301
<input type="checkbox"/>	L11	l9 and cell plate	0
	<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<input type="checkbox"/>	L10	l9 and cell plate	3
<input type="checkbox"/>	L9	L8 and overlap\$ adj3 gate	26
<input type="checkbox"/>	L8	L7 and high dielectric constant	720
<input type="checkbox"/>	L7	L6 and DRAM	3954
<input type="checkbox"/>	L6	L5 and substrate	7953
<input type="checkbox"/>	L5	L4 and (tantalum oxide or aluminum oxide or silicon nitride or oxynitride or oxynitride)	8063
<input type="checkbox"/>	L4	L3 and cell\$	17056
<input type="checkbox"/>	L3	L2 and gate adj3 (oxide or insulat\$ or dielectric\$)	21458
<input type="checkbox"/>	L2	L1 and transistor	94080
<input type="checkbox"/>	L1	memory	483582

END OF SEARCH HISTORY

**VIET Q. NGUYEN**  
**PRIMARY EXAMINER**